

**Notice of References Cited**Application/Control No.  
**10/043,004**Applicant(s)/Patent Under Reexam  
**Forneck et al.**Examiner  
**Lien Tran**Art Unit  
**1761**

Page 1 of 1

**U.S. PATENT DOCUMENTS**

	Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Name	Classification <sup>2</sup>	
A	4,582,711	4/1986	Durst	426	128
B	6,436,458	8/2002	Kuechle et al.	426	128
C	5,167,973	12/1992	Snyder	426	120
D	5,695,798	12/1997	Rozzano	426	120
E	5,792,499	8/1998	Atwell	426	549
F					
G					
H					
I					
J					
K					
L					
M					

**FOREIGN PATENT DOCUMENTS**

	Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Country	Name	Classification <sup>2</sup>	
N						
O						
P						
Q						
R						
S						
T						

**NON-PATENT DOCUMENTS**

	Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages				
U					
V					
W					
X					

<sup>1</sup> A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(a).<sup>1</sup> Dates in MM-YYYY format are publication dates.<sup>2</sup> Classifications may be U.S. or foreign.